

PCTEST ENGINEERING LABORATORY, INC.

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MEASUREMENT REPORT FCC Part 24 & 27 LTE

Applicant Name:

Samsung Electronics, Co. Ltd. 129, Samsung-ro, Maetan dong, Yeongtong-gu, Suwon-si Gyeonggi-do 443-742, Korea Date of Testing: 7/8-7/16/2014 Test Site/Location: PCTEST Lab., Columbia, MD, USA Test Report Serial No.: 0Y1407011334.A3L

A3LSPHL520

FCC ID : APPLICANT:

SAMSUNG ELECTRONICS, CO. LTD.

Application Type: FCC Classification: FCC Rule Part(s): Test Procedure(s): EUT Type: Model(s): Test Device Serial No.: Class II Permissive Change: Original Grant Date: Class II Permissive Change PCS Licensed Transmitter Held to Ear (PCE) §2; §24; §27 ANSI/TIA-603-C-2004, KDB 971168 v02r01 Portable Handset SPH-L520 *identical prototype* [S/N: #81, EMC, SAR B41] Please see FCC change document 9/4/2013

				EI	RP
Mode	Tx Frequency (MHz)	Emission Designator	Modulation	Max. Power (W)	Max. Power (dBm)
LTE Band 25	1850.7 - 1914.3	1M13G7D	QPSK	0.090	19.54
LTE Band 25	1850.7 - 1914.3	1M13W7D	16QAM	0.077	18.85
LTE Band 25	1857.5 - 1907.5	13M5G7D	QPSK	0.085	19.31
LTE Band 25	1857.5 - 1907.5	13M5W7D	16QAM	0.073	18.61
LTE Band 25	1860 - 1905	17M9G7D	QPSK	0.089	19.48
LTE Band 25	1860 - 1905	18M0W7D	16QAM	0.072	18.60
LTE Band 41	2499 - 2687.5	4M50G7D	QPSK	0.088	19.47
LTE Band 41	2499 - 2687.5	4M49W7D	16QAM	0.064	18.09

This equipment has been shown to be capable of compliance with the applicable technical standards as indicated in the measurement report and was tested in accordance with the measurement procedures specified in §2.947. Test results reported herein relate only to the item(s) tested.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

dy Ortanez



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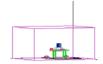


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MEASUREMENT REPORT FCC Part 24 & 27



§2.1033 General Information

APPLICANT:	Samsung Electronics, Co	. Ltd.		
APPLICANT ADDRESS:	129, Samsung-ro, Maeta	n dong,		
	Yeongtong-gu, Suwon-si,	, Gyeonggi-do 443-74	2, Korea	
TEST SITE:	PCTEST ENGINEERING	LABORATORY, INC		
TEST SITE ADDRESS:	7185 Oakland Mills Road	, Columbia, MD 2104	5 USA	
FCC RULE PART(S):	§2; §24; §27			
BASE MODEL:	SPH-L520			
FCC ID:	A3LSPHL520			
FCC CLASSIFICATION:	PCS Licensed Transmitte	er Held to Ear (PCE)		
Test Device Serial No.:	#81, EMC, SAR B41	Production	Pre-Production	Engineering
DATE(S) OF TEST:	7/8-7/16/2014			
TEST REPORT S/N:	0Y1407011334.A3L			

Test Facility / Accreditations

Measurements were performed at PCTEST Engineering Lab located in Columbia, MD 21046, U.S.A.

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- PCTEST facility is an FCC registered (PCTEST Reg. No. 159966) test facility with the site description report on file and has met all the requirements specified in Section 2.948 of the FCC Rules and Industry Canada (2451B-1).
- PCTEST Lab is accredited to ISO 17025 by U.S. National Institute of Standards and Technology (NIST) under the National Voluntary Laboratory Accreditation Program (NVLAP Lab code: 100431-0) in EMC, FCC and Telecommunications.
- PCTEST Lab is accredited to ISO 17025-2005 by the American Association for Laboratory Accreditation (A2LA) in Specific Absorption Rate (SAR) testing, Hearing Aid Compatibility (HAC) testing, CTIA Test Plans, and wireless testing for FCC and Industry Canada Rules.
- PCTEST Lab is a recognized U.S. Conformity Assessment Body (CAB) in EMC and R&TTE (n.b. 0982) under the U.S.-EU Mutual Recognition Agreement (MRA).
- PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to ISO/IEC Guide 65 by the American National Standards Institute (ANSI) in all scopes of FCC Rules and Industry Canada Standards (RSS).
- PCTEST facility is an IC registered (2451B-1) test laboratory with the site description on file at Industry Canada.
- PCTEST is a CTIA Authorized Test Laboratory (CATL) for AMPS, CDMA, and EvDO wireless devices and for Over-the-Air (OTA) Antenna Performance testing for AMPS, CDMA, GSM, GPRS, EGPRS, UMTS (W-CDMA), CDMA 1xEVDO, and CDMA 1xRTT.

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INTRODUCTION 1.0

1.1 Scope

Measurement and determination of electromagnetic emissions (EME) of radio frequency devices including intentional and/or unintentional radiators for compliance with the technical rules and regulations of the Federal Communications Commission and the Industry Canada Certification and Engineering Bureau.

1.2 Testing Facility

The map below shows the location of the PCTEST LABORATORY, its proximity to the FCC Laboratory, the Columbia vicinity, the Baltimore-Washington Internt'I (BWI) airport, the city of Baltimore and the Washington, DC area. (See Figure 1-1).

These measurement tests were conducted at the PCTEST Engineering Laboratory, Inc. facility located at 7185 Oakland Mills Road, Columbia, MD 21046. The site coordinates are 39° 10'23" N latitude and 76° 49'50" W longitude. The facility is 0.4 miles North of the FCC laboratory, and the ambient signal and ambient signal strength are approximately equal to those of the FCC laboratory. The detailed description of the measurement facility was found to be in compliance with the requirements of § 2.948 according to ANSI C63.4-2003 on February 15, 2012.

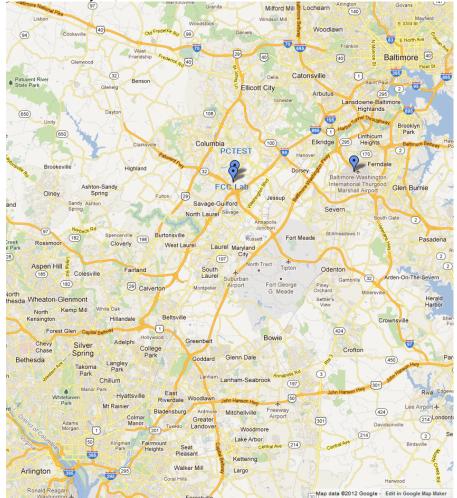


Figure 1-1. Map of the Greater Baltimore and Metropolitan Washington, D.C. area

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2.0 PRODUCT INFORMATION

2.1 Equipment Description

The Equipment Under Test (EUT) is the **Samsung Portable Handset FCC ID: A3LSPHL520**. The test data contained in this report pertains only to the emissions due to the EUT's LTE function.

2.2 Device Capabilities

This device contains the following capabilities:

850/1900 CDMA (BC0, BC1, BC10), Multi-band LTE, 802.11a/b/g/n WLAN (DTS/NII), Bluetooth (1x, EDR, LE), NFC

2.3 EMI Suppression Device(s)/Modifications

No EMI suppression device(s) were added and no modifications were made during testing.

2.4 Labeling Requirements

Per 2.925

The FCC identifier shall be permanently affixed to the equipment and shall be readily visible to the purchaser at the time of purchase.

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3.0 DESCRIPTION OF TESTS

3.1 Measurement Procedure

The measurement procedures described in the document titled "Land Mobile FM or PM – Communications Equipment – Measurements and Performance Standards" (ANSI/TIA-603-C-2004) and "Procedures for Compliance Measurement of the Fundamental Emission Power of Licensed Wideband (> 1 MHz) Digital Transmission Systems" (KDB 971168) were used in the measurement of the **Samsung Portable Handset FCC ID: A3LSPHL520.**

3.2 BRS/EBS Frequency Range §27.5(i)(2)

<u>2496-2690 MHz bands</u>. The following frequencies are available for licensing pursuant to this part in the 2496-2690 MHz band:

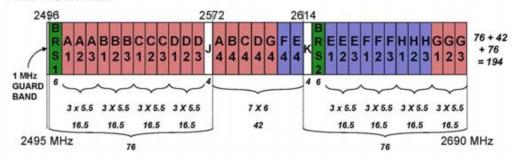
Lower Band Segment	Middle Band Segment	Upper Band Segment
BRS Channel 1: 2496-2502 MHz or 2150-2156 MHz	EBS Channel A4: 2572-2578 MHz	BRS Channel KH1: 2614.00000-2614.33333 MHz.
EBS Channel A1: 2502-2507.5 MHz	EBS Channel B4: 2578-2584 MHz	BRS Channel KH2: 2614.33333-2614.66666 MHz.
EBS Channel A2: 2507.5-2513 MHz	EBS Channel C4: 2584-2590 MHz	BRS Channel KH3: 2614.66666-2615.00000 MHz.
EBS Channel A3: 2513-2518.5 MHz	EBS Channel D4: 2590-2596 MHz	EBS Channel KG1: 2615.00000-2615.33333 MHz.
EBS Channel B1: 2518.5-2524 MHz	EBS Channel G4: 2596-2602 MHz	EBS Channel KG2: 2615.33333-2615.66666 MHz.
EBS Channel B2: 2524-2529.5 MHz	BRS/EBS Channel F4: 2602-2608 MHz	EBS Channel KG3: 2615.66666-2616.00000 MHz.
EBS Channel B3: 2529.5-2535 MHz	BRS/EBS Channel E4: 2608-2614 MHz	BRS Channel KF1: 2616.00000-2616.33333 MHz.
EBS Channel C1: 2535-2540.5 MHz		BRS Channel KF2: 2616.33333-2616.66666 MHz.
EBS Channel C2: 2540.5-2546 MHz		BRS Channel KF3: 2616.66666-2617.00000 MHz.
EBS Channel C3: 2546-2551.5 MHz		BRS Channel KE1: 2617.00000-2617.33333 MHz.
EBS Channel D1: 2551.5-2557 MHz		BRS Channel KE2: 2617.33333-2617.66666 MHz.
EBS Channel D2: 2557-2562.5 MHz		BRS Channel KE3: 2617.66666-2618.00000 MHz.
EBS Channel D3: 2562.5-2568 MHz		BRS Channel 2: 2618-2624 MHz or 2156-2162 MHz.
EBS Channel JA1: 2568.00000-2568.33333 MHz		BRS Channel 2A: 2618-2624 MHz or 2156-2160 MHz.
EBS Channel JA2: 2568.33333-2568.66666 MHz		BRS/EBS Channel E1: 2624-2629.5 MHz.
EBS Channel JA3: 2568.66666-2569.00000 MHz		BRS/EBS Channel E2: 2629.5-2635 MHz.
EBS Channel JB1: 2569.00000-2569.33333 MHz		BRS/EBS Channel E3: 2635-2640.5 MHz.
EBS Channel JB2: 2569.33333-2569.66666 MHz		BRS/EBS Channel F1: 2640.5-2646 MHz
EBS Channel JB3: 2569.66666-2570.00000 MHz		BRS/EBS Channel F2: 2646-2651.5 MHz.
EBS Channel JC1: 2570.00000-2570.33333 MHz		BRS/EBS Channel F3: 2651.5-2657 MHz
EBS Channel JC2: 2570.33333-2570.666666 MHz		BRS Channel H1: 2657-2662.5 MHz.
EBS Channel JC3: 2570.66666-2571.00000 MHz		BRS Channel H2: 2662.5-2668 MHz.
EBS Channel JD1: 2571.00000-2571.33333 MHz		BRS Channel H3: 2668-2673.5 MHz.
EBS Channel JD2: 2571.33333-2571.666666 MHz		EBS Channel G1: 2673.5-2679 MHz.
EBS Channel JD3: 2571.66666-2572.00000 MHz		EBS Channel G2: 2679-2684.5 MHz.
		EBS Channel G3: 2684.5-2690 MHz.

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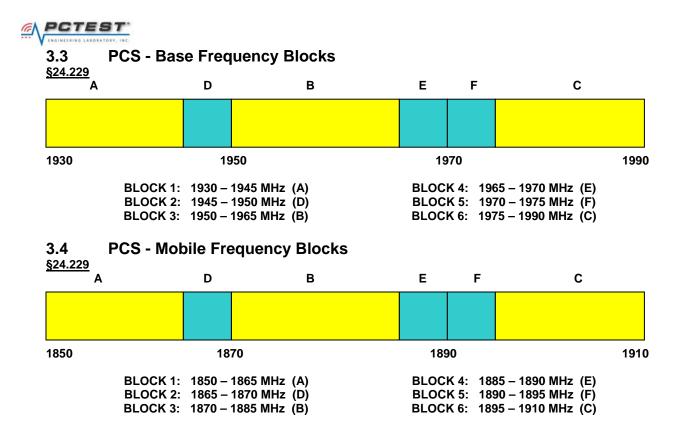


BRS-EBS BAND PLANS: POST-TRANSITION AT 2495-2690 MHz

POST-TRANSITION



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3.5 Radiated Power and Radiated Spurious Emissions §2.1053 §24.232(c) §24.238(a) §27.53(m)

The radiated test facilities consisted of an indoor 3 meter semi-anechoic chamber used for final measurements and exploratory measurements, when necessary. The measurement area is contained within the semi-anechoic chamber which is shielded from any ambient interference. The test site inside the chamber is a 6m x 5.2m elliptical, obstruction-free area in accordance with Clause 5, Figure 5.7 of ANSI C63.4-2009. For measurements above 1GHz absorbers are arranged on the floor between the turn table and the antenna mast in such a way so as to maximize the reduction of reflections. For measurements below 1GHz, the absorbers are removed. An ETS Lindgren Model 2188 raised turntable is used for radiated measurement. It is a continuously rotatable, remote-controlled, metallic turntable and 2 meters (6.56 ft.) in diameter. The turn table is flush with the raised floor of the chamber in order to maintain its function as a ground plane. A 78cm high PVC support structure is placed on top of the turntable. A $\frac{3}{4}$ " (~1.9cm) sheet of high density polyethylene is used as the table top and is placed on top of the PVC supports to bring the total height of the table to 80cm.

The equipment under test was transmitting while connected to its integral antenna and is placed on a wooden turntable 80cm above the ground plane and 3 meters from the receive antenna. The receive antenna height is adjusted between 1 and 4 meter height, the turntable is rotated through 360 degrees, and the EUT is manipulated through all orthogonal planes representative of its typical use to achieve the highest reading on the receive spectrum analyzer. Radiated power levels are also investigated with the receive antenna horizontally and vertically polarized. The maximized power level is recorded using the spectrum analyzer "Channel Power" function with the integration band set to the emissions' occupied bandwidth, a RMS detector, RBW = 100kHz, VBW = 300kHz, and a 1 second sweep time over a minimum of 10 sweeps, per the guidelines of KDB 971168.

Per the guidance of ANSI/TIA-603-C-2004, a half-wave dipole is then substituted in place of the EUT. For emissions above 1GHz, a horn antenna is substituted in place of the EUT. The substitute antenna is driven by a signal generator with the level of the signal generator being adjusted to obtain the same receive spectrum analyzer level previously recorded from the spurious emission from the EUT. The power of the emission is calculated using the following formula:

$$P_{d [dBm]} = P_{g [dBm]} - cable loss_{[dB]} + antenna gain_{[dBd/dBi]}$$

Where, P_d is the dipole equivalent power, P_g is the generator output into the substitution antenna, and the antenna gain is the gain of the substitute antenna used relative to either a half-wave dipole (dBd) or an isotropic source (dBi). The substitute level is equal to $P_{g \text{ [dBm]}}$ – cable loss $_{\text{[dB]}}$.

The calculated P_d levels are then compared to the absolute spurious emission limit of -13dBm which is equivalent to the required minimum attenuation of 43 + 10log₁₀(Power _[Watts]). For Band 41, the calculated P_d levels are compared to the absolute spurious emission limit of -25dBm which is equivalent to the required minimum attenuation of 55 + 10log₁₀(Power _[Watts]).

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4.0 TEST EQUIPMENT CALIBRATION DATA

Test Equipment Calibration is traceable to the National Institute of Standards and Technology (NIST).

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
-	LTx1	Licensed Transmitter Cable Set	1/29/2014	Annual	1/29/2015	N/A
-	RE1	Radiated Emissions Cable Set (UHF/EHF)	5/29/2014	Annual	5/29/2015	N/A
Agilent	8447D	Broadband Amplifier	6/2/2014	Annual	6/2/2015	1937A03348
Agilent	E5515C	Wireless Communications Test Set	3/18/2014	Annual	3/18/2015	GB46110872
Agilent	N9020A	MXA Signal Analyzer	10/29/2013	Annual	10/29/2014	US46470561
Agilent	N9030A	PXA Signal Analyzer (26.5GHz)	5/8/2014	Annual	5/8/2015	MY49432391
Com-Power	AL-130	9kHz - 30MHz Loop Antenna	6/26/2013	Biennial	6/26/2015	121034
ETS Lindgren	3117	1-18 GHz DRG Horn (Medium)	4/8/2014	Biennial	4/8/2016	125518
ETS Lindgren	3160-09	18-26.5 GHz Standard Gain Horn	6/17/2014	Biennial	6/17/2016	135427
ETS Lindgren	3164-08	Quad Ridge Horn Antenna	3/12/2014	Biennial	3/12/2016	128337
Gigatronics	80701A	(0.05-18GHz) Power Sensor	10/30/2013	Annual	10/30/2014	1833460
Gigatronics	8651A	Universal Power Meter	10/30/2013	Annual	10/30/2014	8650319
K & L	11SH10-3075/U18000	High Pass Filter	5/2/2014	Annual	5/2/2015	2
Rhode & Schwarz	TS-PR18	Pre-Amplifier	6/12/2014	Annual	6/12/2015	101622
Rohde & Schwarz	CMW500	Radio Communication Tester	10/18/2013	Annual	10/18/2014	100976
Rohde & Schwarz	TS-PR18	1-18 GHz Pre-Amplifier	3/5/2014	Annual	3/5/2015	100071
Rohde & Schwarz	TS-PR26	18-26.5 GHz Pre-Amplifier	3/12/2014	Annual	3/12/2015	100040
Rohde & Schwarz	ESU26	EMI Test Receiver (26.5GHz)	1/27/2014	Annual	1/27/2015	100342
Schwarzbeck	UHA 9105	Dipole Antenna (400 - 1GHz) Rx	11/21/2013	Biennial	11/21/2015	9105-2404
Schwarzbeck	UHA 9105	Dipole Antenna (400 - 1GHz) Tx	11/21/2013	Biennial	11/21/2015	9105-2403
Sunol	JB5	Bi-Log Antenna (30M - 5GHz)	1/28/2014	Biennial	1/28/2016	A051107

Table 4-1. Test Equipment

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5.0 SAMPLE CALCULATIONS

Emission Designator

QPSK Modulation

Emission Designator = 8M62G7D

LTE BW = 8.62 MHz G = Phase Modulation 7 = Quantized/Digital Info D = Amplitude/Angle Modulated

16QAM Modulation

Emission Designator = 8M45W7D

LTE BW = 8.45 MHz W = Amplitude/Angle Modulated 7 = Quantized/Digital Info D = Combination (Audio/Data)

Spurious Radiated Emission – LTE Band

Example: Middle Channel LTE Mode 2nd Harmonic (1564 MHz)

The average spectrum analyzer reading at 3 meters with the EUT on the turntable was -81.0 dBm. The gain of the substituted antenna is 8.1 dBi. The signal generator connected to the substituted antenna terminals is adjusted to produce a reading of -81.0 dBm on the spectrum analyzer. The loss of the cable between the signal generator and the terminals of the substituted antenna is 2.0 dB at 1564 MHz. So 6.1 dB is added to the signal generator reading of -30.9 dBm yielding -24.80 dBm. The fundamental EIRP was 25.501 dBm so this harmonic was 25.501 dBm – (-24.80).

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6.0 TEST RESULTS

6.1 Summary

Company Name:	Samsung Electronics, Co. Ltd.
FCC ID:	A3LSPHL520
FCC Classification:	PCS Licensed Transmitter Held to Ear (PCE)
Mode(s):	LTE

FCC Part Section(s)	Test Description Test Limit Test Conditio		Test Condition	Result	Reference
TRANSMITTER MOD	E (TX)				
2.1049	Occupied Bandwidth	N/A		PASS	Section 6.2
2.1051 24.238(a)	Band Edge / Conducted Spurious Emissions	> 43 + 10log ₁₀ (P[Watts]) at Band Edge and for all out-of- band emissions		PASS	Section 6.3, 6.4
27.53(m)	Band Edge / Conducted Spurious Emissions	 > 43 + 10log₁₀ (P[Watts]) at channel edges and > 55 + 10log₁₀ (P[Watts]) at 5.5MHz away and beyond channel edges 	CONDUCTED	PASS	Section 6.3, 6.4
24.232(d)	Peak-Average Ratio	< 13 dB	-	PASS	Section 6.5
2.1046	Transmitter Conducted Output Power	N/A		PASS	See RF Exposure Report
2.1055. 24.235 27.54	Frequency Stability	Fundamental emissions stay within authorized frequency block (Part 24, 27)		PASS	Section 6.7
24.232(c) 27.50(h.2)	Equivalent Isotropic Radiated Power (Band 25 41)	< 2 Watts max. EIRP	RADIATED	PASS	Section 6.6
	Table 6	-1. Summary of Test Resu	lts	-	

Notes:

- 1) All modes of operation and data rates were investigated. The test results shown in the following sections represent the worst case emissions.
- 2) The analyzer plots (Sections 6.2, 6.3, 6.4, 6.5) were all taken with a correction table loaded into the analyzer. The correction table was used to account for the losses of the cables, directional couplers, and attenuators used as part of the system to maintain a link between the call box and the EUT at all frequencies of interest.
- 3) All antenna port conducted emissions testing was performed on a test bench with the antenna port of the EUT connected to the spectrum analyzer through calibrated cables, attenuators, and couplers.
- 4) For conducted spurious emissions, automated test software was used to measure emissions and capture the corresponding plots necessary to show compliance. The measurement software utilized is PCTEST "LTE Automation", Version 2.4.

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6.2 Occupied Bandwidth §2.1049

Test Overview

The occupied bandwidth, that is the frequency bandwidth such that, below its lower and above its upper frequency limits, the mean powers radiated are each equal to 0.5 percent of the total mean power radiated by a given emission shall be measured. All modes of operation were investigated and the worst case configuration results are reported in this section.

Test Procedure Used

KDB 971168 v02r01 - Section 4.2

Test Settings

- 1. The signal analyzer's automatic bandwidth measurement capability was used to perform the 99% occupied bandwidth and the 26dB bandwidth. The bandwidth measurement was not influenced by any intermediate power nulls in the fundamental emission.
- 2. RBW = 1 5% of the expected OBW
- 3. VBW \geq 3 x RBW
- 4. Detector = Peak
- 5. Trace mode = max hold
- 6. Sweep = auto couple
- 7. The trace was allowed to stabilize
- 8. If necessary, steps 2 7 were repeated after changing the RBW such that it would be within

1 – 5% of the 99% occupied bandwidth observed in Step 7

Test Setup

The EUT and measurement equipment were set up as shown in the diagram below.

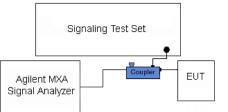


Figure 6-1. Test Instrument & Measurement Setup

Test Notes

None.

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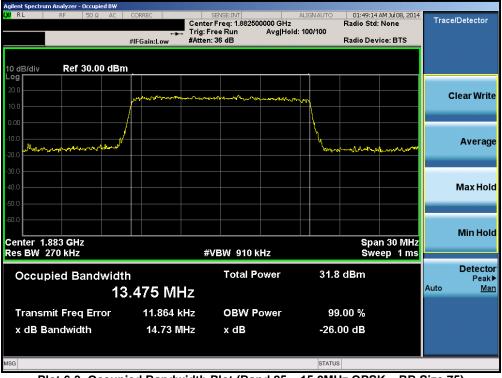
Plot 6-1. Occupied Bandwidth Plot (Band 25 – 1.4MHz QPSK – RB Size 6)



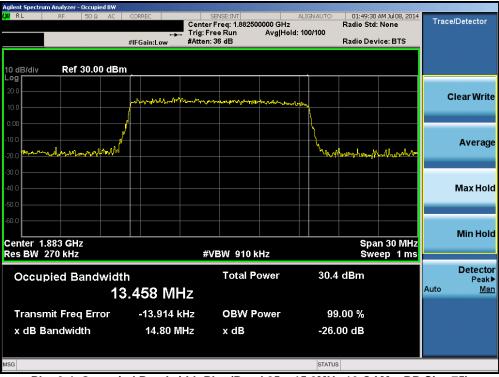
Plot 6-2. Occupied Bandwidth Plot (Band 25 – 1.4MHz 16-QAM – RB Size 6)

FCC ID: A3LSPHL520	PCTEST	FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	SUNG	Reviewed by: Quality Manager
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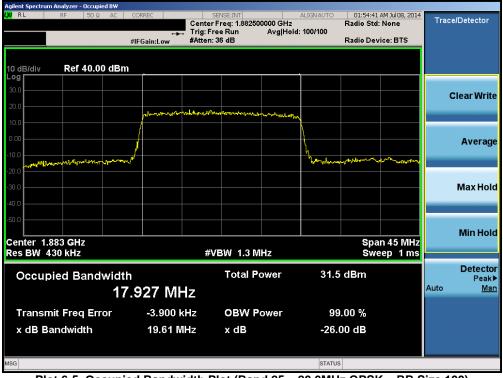
Plot 6-3. Occupied Bandwidth Plot (Band 25 – 15.0MHz QPSK – RB Size 75)



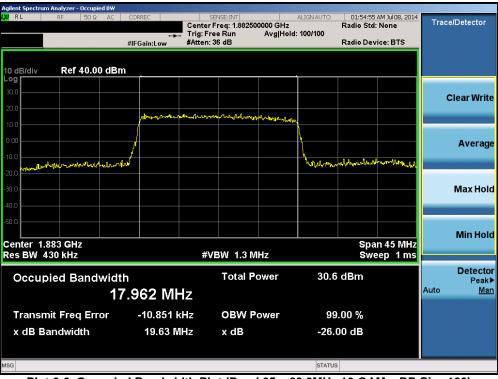
Plot 6-4. Occupied Bandwidth Plot (Band 25 – 15.0MHz 16-QAM – RB Size 75)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	MSUNG	Reviewed by: Quality Manager
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Plot 6-5. Occupied Bandwidth Plot (Band 25 - 20.0MHz QPSK - RB Size 100)



Plot 6-6. Occupied Bandwidth Plot (Band 25 – 20.0MHz 16-QAM – RB Size 100)

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Plot 6-7. Occupied Bandwidth Plot (Band 41 – 5.0MHz QPSK – RB Size 25)



Plot 6-8. Occupied Bandwidth Plot (Band 41 – 5.0MHz 16-QAM – RB Size 25)

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Spurious and Harmonic Emissions at Antenna Terminal 6.3 §2.1051 §24.238(a) §27.53(m)

Test Overview

The level of the carrier and the various conducted spurious and harmonic frequencies is measured by means of a calibrated spectrum analyzer. The spectrum is scanned from the lowest frequency generated in the equipment up to a frequency including its 10th harmonic. All out of band emissions are measured with a spectrum analyzer connected to the antenna terminal of the EUT while the EUT is operating at its maximum duty cycle, at maximum power, and at the appropriate frequencies. All data rates were investigated to determine the worst case configuration. All modes of operation were investigated and the worst case configuration results are reported in this section.

The minimum permissible attenuation level of any spurious emission is $43 + \log_{10}(P_{IWattsl})$, where P is the transmitter power in Watts. For Band 41, the minimum permissible attenuation level of any spurious emission is $55 + \log_{10}(P_{[Watts]})$.

Test Procedure Used

KDB 971168 v02r01 - Section 6.0

Test Settings

- 1. Start frequency was set to 30MHz and stop frequency was set to at least 10 * the fundamental frequency (separated into at least two plots per channel)
- 2. Detector = RMS
- 3. Trace mode = max hold
- 4. Sweep time = auto couple
- 5. The trace was allowed to stabilize
- 6. Please see test notes below for RBW and VBW settings

Test Setup

The EUT and measurement equipment were set up as shown in the diagram below.

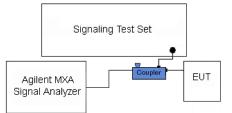


Figure 6-2. Test Instrument & Measurement Setup

Test Notes

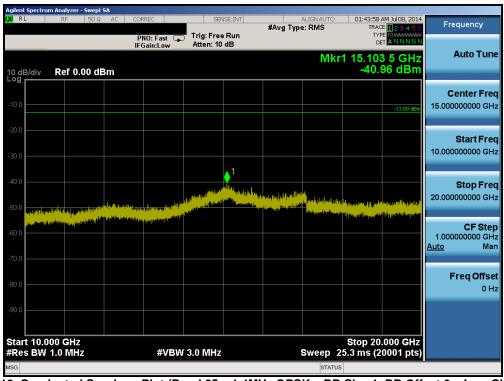
Compliance with the applicable limits is based on the use of measurement instrumentation employing a resolution bandwidth of 100 kHz or greater for frequencies less than 1 GHz and 1 MHz or greater for frequencies greater than 1 GHz. However, in the 1 MHz bands immediately outside and adjacent to the frequency block a resolution bandwidth of at least one percent of the emission bandwidth of the fundamental emission of the transmitter may be employed. The emission bandwidth is defined as the width of the signal between two points, one below the carrier center frequency and one above the carrier center frequency, outside of which all emission are attenuated at least 26 dB below the transmitter power. Many of the following conducted spurious emission plots for Band 41 do not extend to completely cover the necessary frequencies. In order to demonstrate compliance, integration plots with a 1MHz bandwidth covering the remaining frequencies have been provided.

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L <mark>au</mark> RL	RF	50 9	R AC CO	RREC		JSE:INT	#Avg Type	ALIGN AUTO e: RMS	TRAC	AM Jul 08, 2014 E <mark>1 2 3 4 5 6</mark>	Frequency
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											Center Freq
15.0											5.015000000 GHz
5.00											Start Freq
-5.00											30.000000 MHz
										-13.00 dBm	
-15.0											Stop Freq
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Plot 6-9. Conducted Spurious Plot (Band 25 – 1.4MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)



Plot 6-10. Conducted Spurious Plot (Band 25 – 1.4MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	Reviewed by: Quality Manager				
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RL 0 dB/div	RF 50 Ω	AC CORREC PNO: Fast File File File File File File File File		#Avg Type	ALIGN AUTO	TRAC	AM Jul 08, 2014 E 123456 E MWWWWWW T A N N N N N	Frequency
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		#VBV	* 3.0 WIA Z		Sweep 1.	r.5 ms (2	boor pis)	

Plot 6-11. Conducted Spurious Plot (Band 25 – 1.4MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 6-12. Conducted Spurious Plot (Band 25 – 1.4MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	Reviewed by: Quality Manager				
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X/RL	RF 50 S	Σ AC C	ORREC	SEN	JSE:INT	#Avg Typ			M Jul 08, 2014	Frequency
			PNO: Fast 🖵 IFGain:Low	Trig: Free Atten: 36		HULA I M	e. 14115	TYPE	ANNNNN	
10 dB/div	Ref 25.00	dBm					Mk	r1 9.356 -24.3	4 GHz 2 dBm	Auto Tune
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MSG							STATUS			

Plot 6-13. Conducted Spurious Plot (Band 25 – 1.4MHz QPSK – RB Size 1, RB Offset 0 – High Channel)



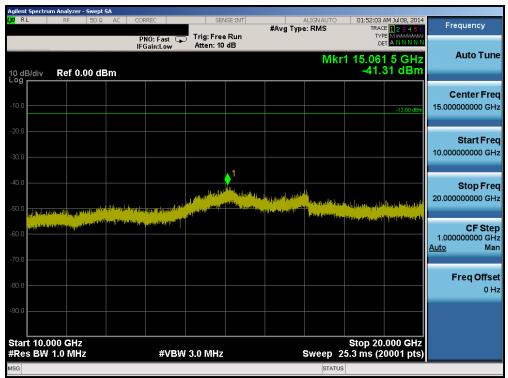
Plot 6-14. Conducted Spurious Plot (Band 25 – 1.4MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	Reviewed by: Quality Manager					
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ISG							STATUS			

Plot 6-15. Conducted Spurious Plot (Band 25 – 15.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)



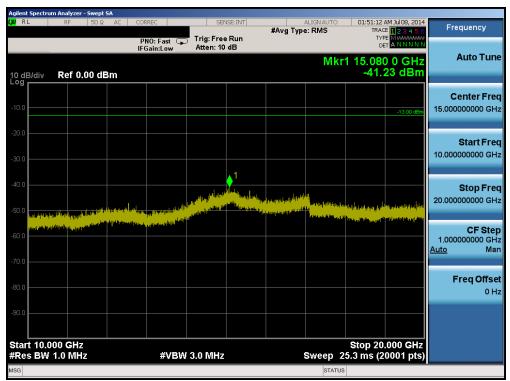
Plot 6-16. Conducted Spurious Plot (Band 25 – 15.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	Reviewed by: Quality Manager				
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i5.0										Freq Offs
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tart 30 N							_	Stop 10.00	GHz	
	1.0 MHz		#VBW	3.0 MHz				7.3 ms (2000	T pts)	
G							STATUS	5		

Plot 6-17. Conducted Spurious Plot (Band 25 – 15.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



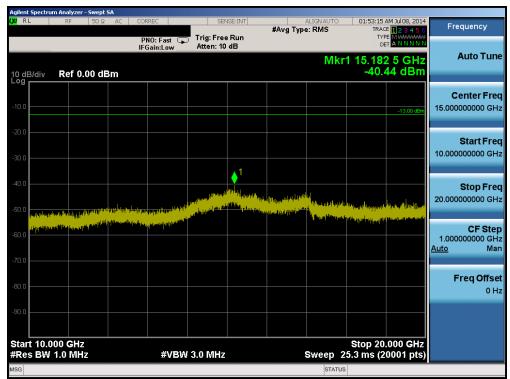
Plot 6-18. Conducted Spurious Plot (Band 25 – 15.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	ING	Reviewed by: Quality Manager			
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<mark>X/</mark> RL	RF	50Ω AC	CORREC		SE:INT	#Avg Typ	ALIGN AUTO e: RMS	TRACE	M Jul 08, 2014	Frequency
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//SG							STATUS			

Plot 6-19. Conducted Spurious Plot (Band 25 – 15.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)



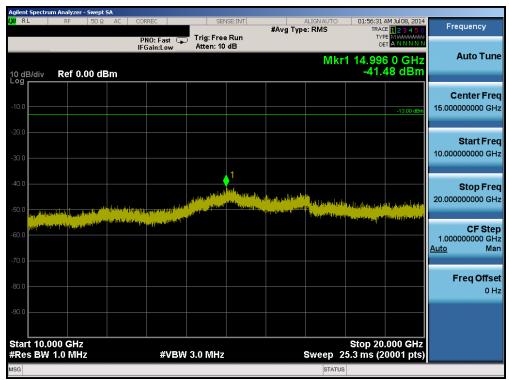
Plot 6-20. Conducted Spurious Plot (Band 25 – 15.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	Reviewed by: Quality Manager
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-55.0										Freq Offset 0 Hz
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#Res BW			#VBW	3.0 MHz			Sweep 1	7.3 ms (20	0001 pts)	
MSG							STATUS	;		

Plot 6-21. Conducted Spurious Plot (Band 25 – 20.0MHz QPSK – RB Size 1, RB Offset 0– Low Channel)



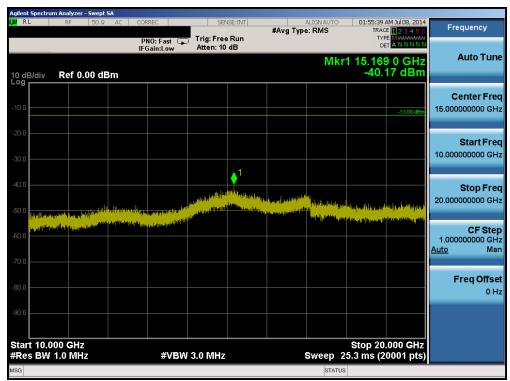
Plot 6-22. Conducted Spurious Plot (Band 25 – 20.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	UNG	Reviewed by: Quality Manager
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	ım Analyzer - Swer								_
X/RL	RF 50	Ω AC I	CORREC	SEN	ISE:INT	#Avg Typ	ALIGN AUTO e: RMS	01:55:33 AM Jul 08, 201- TRACE 1 2 3 4 5 (
			PNO: Fast 🖵 IFGain:Low	Trig: Free Atten: 36		•			
10 dB/div	Ref 25.00	dBm					Mk	r1 9.376 4 GHz -25.02 dBm	Auto Tuno
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25.0								-13.00 dBr	Stop Fre 10.000000000 G⊦
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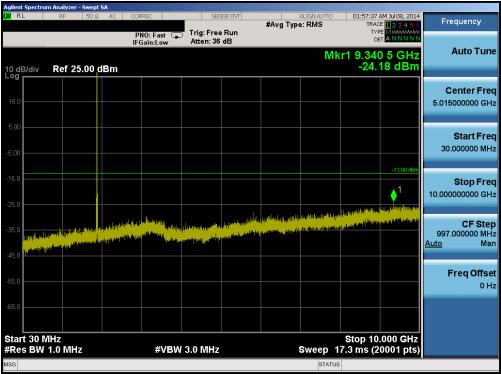
Plot 6-23. Conducted Spurious Plot (Band 25 – 20.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



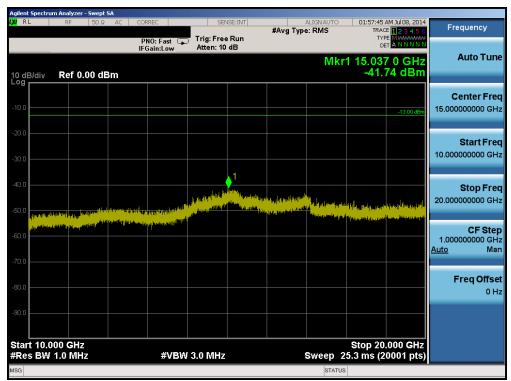
Plot 6-24. Conducted Spurious Plot (Band 25 – 20.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	Reviewed by: Quality Manager
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Plot 6-25. Conducted Spurious Plot (Band 25 – 20.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)



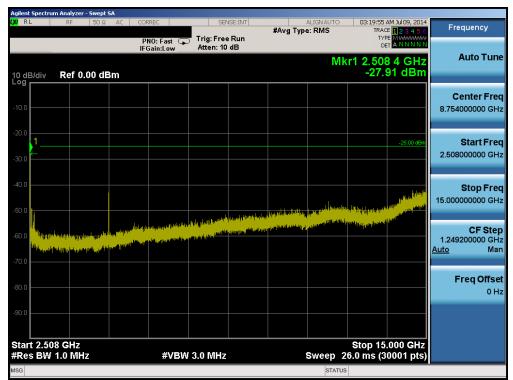
Plot 6-26. Conducted Spurious Plot (Band 25 – 20.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	SAMSUNG	Reviewed by: Quality Manager
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	ım Analyzer - S										
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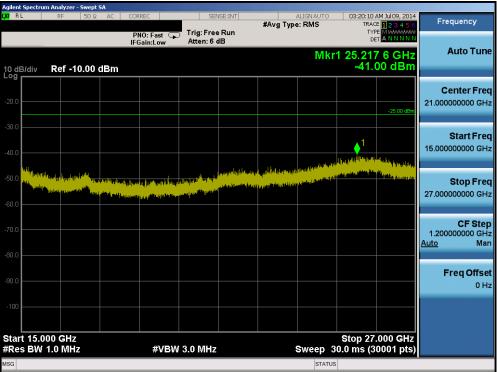
Plot 6-27. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)



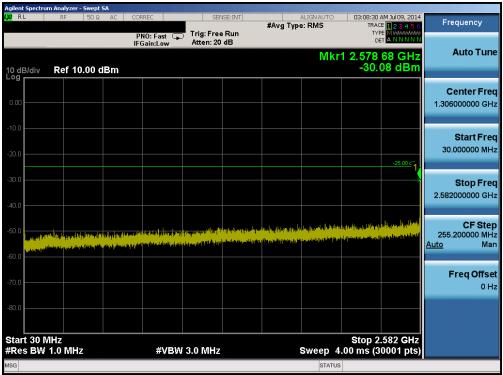
Plot 6-28. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	Reviewed by: Quality Manager
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Plot 6-29. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)



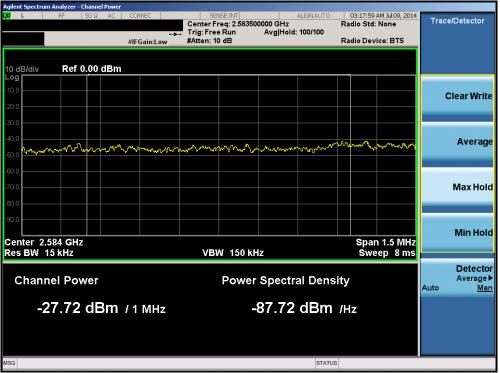
Plot 6-30. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	MSUNG	Reviewed by: Quality Manager						
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Plot 6-31. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



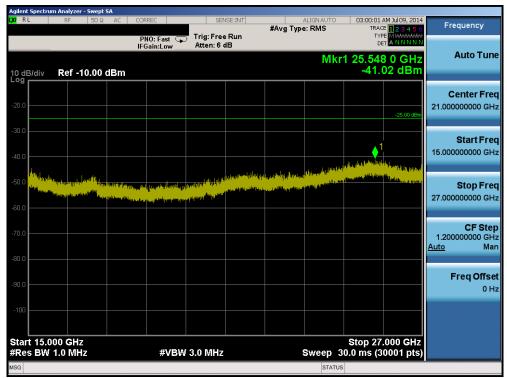
Plot 6-32. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	Reviewed by: Quality Manager
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	pectrum	Analyzer - S	wept SA								
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L											
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	BW 1	.0 MHZ		#VE	W 3.0 MH2					ooor pis)	
MSG								STATUS	5		

Plot 6-33. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 6-34. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	SAMSUNG	Reviewed by: Quality Manager
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	um Analyzer - Swept :									
I,XI RL	RF 50 Ω	AC COF	REC		VSE:INT	#Avg Type	ALIGN AUTO	TRAC	AM Jul 09, 2014 E <mark>1 2 3 4 5 6</mark>	Frequency
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										Start Freq 30.000000 MHz
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· · · · · ·	1.0 MHz		#VBW	3.0 MHz			Sweep 4	.00 ms (3	0001 pts)	
MSG							STATUS	3		

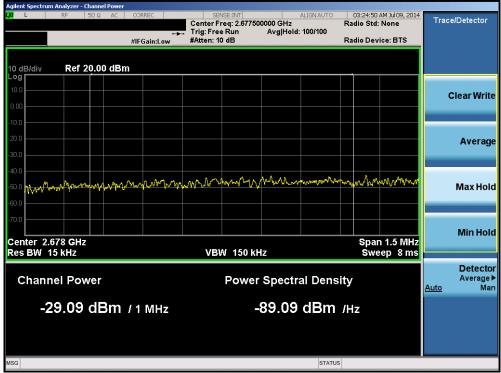
Plot 6-35. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)



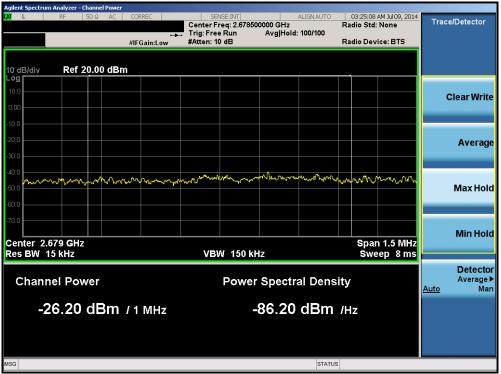
Plot 6-36. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	SAMSUNG	Reviewed by: Quality Manager
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Plot 6-37. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)



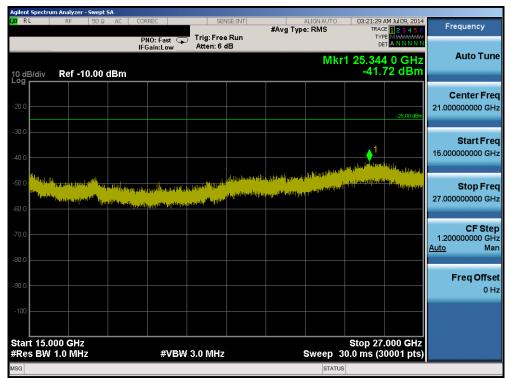
Plot 6-38. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	Reviewed by: Quality Manager
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		n Analyzer - Sw									
l xi ri	L	RF 5	ΟΩ ΑΟ Ο	ORREC	SEN	ISE:INT	#Avg Typ	ALIGN AUTO e: RMS	03:21:20 TRAC	AM Jul 09, 2014	Frequency
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											Center Freq
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-00.0											
		7 GHz 1.0 MHz		#\/B\A	/ 3.0 MHz			Swoon -	Stop 15 6.0 ms (3	.000 GHz	
_	5 DW			#VBV	JUWINZ					000 F pts)	
MSG								STATUS			

Plot 6-39. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)



Plot 6-40. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	SAMSUNG	Reviewed by: Quality Manager
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6.4 Band Edge Emissions at Antenna Terminal §2.1051 §24.238(a) §27.53(m)

Test Overview

All out of band emissions are measured with a spectrum analyzer connected to the antenna terminal of the EUT while the EUT is operating at its maximum duty cycle, at maximum power, and at the appropriate frequencies. All data rates were investigated to determine the worst case configuration. All modes of operation were investigated and the worst case configuration results are reported in this section.

The minimum permissible attenuation level of any spurious emission is $43 + \log_{10}(P_{[Watts]})$, where P is the transmitter power in Watts.

The minimum permissible attenuation level for Band 41 is > 43 + $10\log_{10}$ (P[Watts]) at channel edges and > 55 + $10\log_{10}$ (P[Watts]) at 5.5 MHz away and beyond channel edges.

Test Procedure Used

KDB 971168 v02r01 – Section 6.0

Test Settings

- 1. Start and stop frequency were set such that the band edge would be placed in the center of the plot
- 2. Span was set large enough so as to capture all out of band emissions near the band edge
- 3. RBW \geq 1% of the emission bandwidth
- 4. VBW <u>></u> 3 x RBW
- 5. Detector = RMS
- 6. Number of sweep points $\geq 2 \times \text{Span/RBW}$
- 7. Trace mode = max hold
- 8. Sweep time = auto couple
- 9. The trace was allowed to stabilize

Test Setup

The EUT and measurement equipment were set up as shown in the diagram below.

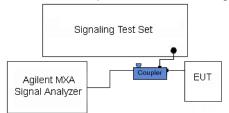


Figure 6-3. Test Instrument & Measurement Setup

Test Notes

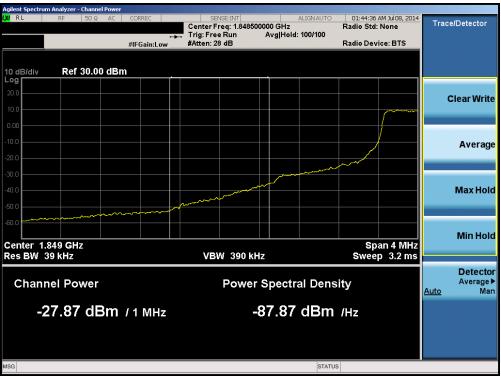
Per 24.238(a) and 27.53(m) in the 1 MHz bands immediately outside and adjacent to the frequency block a resolution bandwidth of at least one percent of the emission bandwidth of the fundamental emission of the transmitter may be employed to demonstrate compliance with the out-of-band emissions limit. The emission bandwidth is defined as the width of the signal between two points, one below the carrier center frequency and one above the carrier center frequency, outside of which all emission are attenuated at least 26 dB below the transmitter power.

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Plot 6-41. Lower Band Edge Plot (Band 25 – 1.4MHz QPSK – RB Size 6)



Plot 6-42. Lower Extended Band Edge Plot (Band 25 – 1.4MHz QPSK – RB Size 6)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	SAMSUNG	Reviewed by: Quality Manager
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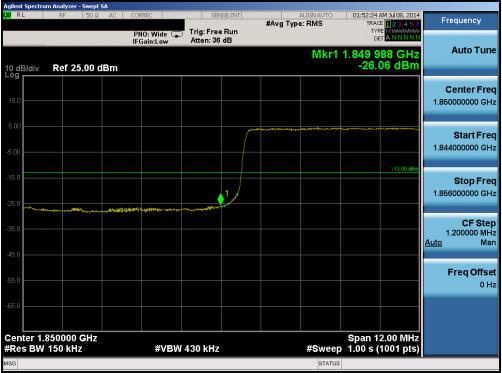
Plot 6-43. Upper Band Edge Plot (Band 25 – 1.4MHz QPSK – RB Size 6)



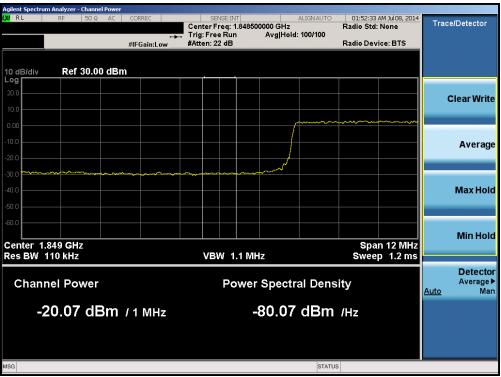
Plot 6-44. Upper Extended Band Edge Plot (Band 25 – 1.4MHz QPSK – RB Size 6)

FCC ID: A3LSPHL520	PCTEST	FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	SAMSUNG	Reviewed by: Quality Manager
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Plot 6-45. Lower Band Edge Plot (Band 25 – 15.0MHz QPSK – RB Size 75)



Plot 6-46. Lower Extended Band Edge Plot (Band 25 – 15.0MHz QPSK – RB Size 75)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	SAMSUNG	Reviewed by: Quality Manager
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Plot 6-47. Upper Band Edge Plot (Band 25 – 15.0MHz QPSK – RB Size 75)



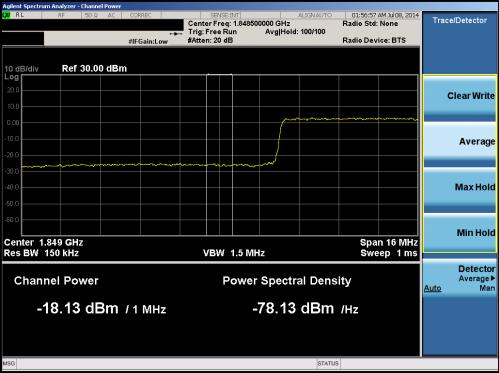
Plot 6-48. Upper Extended Band Edge Plot (Band 25 – 15.0MHz QPSK – RB Size 75)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	SAMSUNG	Reviewed by: Quality Manager
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Plot 6-49. Lower Band Edge Plot (Band 25 - 20.0MHz QPSK - RB Size 100)



Plot 6-50. Lower Extended Band Edge Plot (Band 25 – 20.0MHz QPSK – RB Size 100)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	SAMSUNG	Reviewed by: Quality Manager
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Plot 6-51. Upper Band Edge Plot (Band 25 – 20.0MHz QPSK – RB Size 100)



Plot 6-52. Upper Extended Band Edge Plot (Band 25 – 20.0MHz QPSK – RB Size 100)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	SAMSUNG	Reviewed by: Quality Manager
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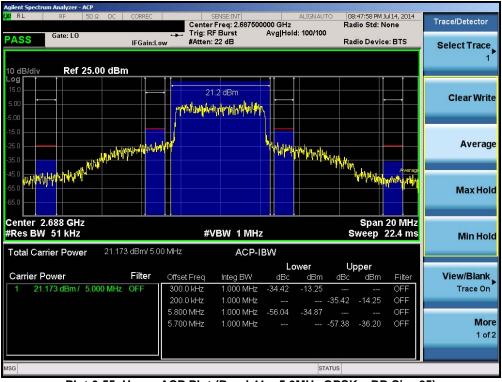
Plot 6-53. Lower ACP Plot (Band 41 – 5.0MHz QPSK – RB Size 25)



Plot 6-54. Mid ACP Plot (Band 41 – 5.0MHz QPSK – RB Size 25)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	Reviewed by: Quality Manager		
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Plot 6-55. Upper ACP Plot (Band 41 – 5.0MHz QPSK – RB Size 25)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	SAMSUNG	Reviewed by: Quality Manager
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6.5 Peak-Average Ratio

Test Overview

A peak to average ratio measurement is performed at the conducted port of the EUT. The spectrum analyzers Complementary Cumulative Distribution Function (CCDF) measurement profile is used to determine the largest deviation between the average and the peak power of the EUT in a given bandwidth. The CCDF curve shows how much time the peak waveform spends at or above a given average power level. The percent of time the signal spends at or above the level defines the probability for that particular power level.

Test Procedure Used

KDB 971168 v02r01 - Section 5.7.1

Test Settings

- 1. The signal analyzer's CCDF measurement profile is enabled
- 2. Frequency = carrier center frequency
- 3. Measurement BW > Emission bandwidth of signal
- 4. The signal analyzer was set to collect one million samples to generate the CCDF curve
- 5. The measurement interval was set depending on the type of signal analyzed. For continuous signals (>98% duty cycle), the measurement interval was set to 1ms. For burst transmissions, the spectrum analyzer is set to use an internal "RF Burst" trigger that is synced with an incoming pulse and the measurement interval is set to less than the duration of the "on time" of one burst to ensure that energy is only captured during a time in which the transmitter is operating at maximum power

Test Setup

The EUT and measurement equipment were set up as shown in the diagram below.

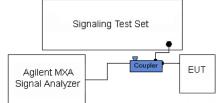


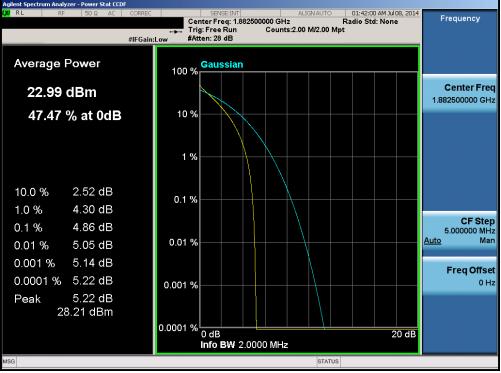
Figure 6-4. Test Instrument & Measurement Setup

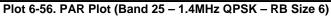
Test Notes

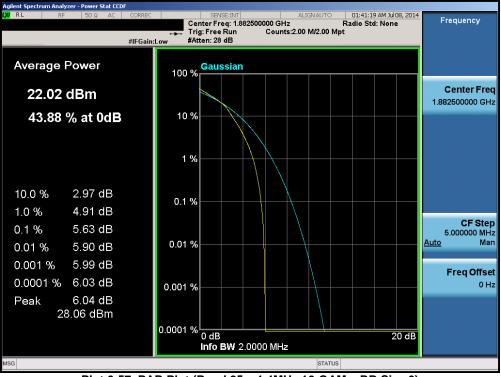
None.

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	Reviewed by: Quality Manager	
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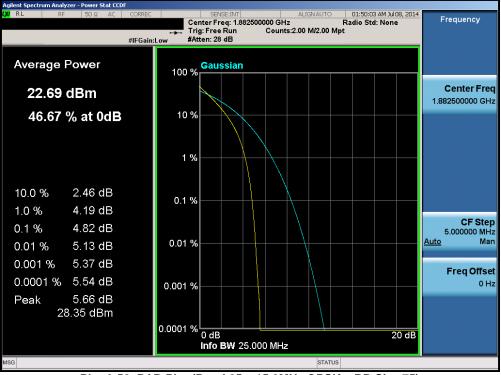


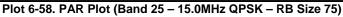


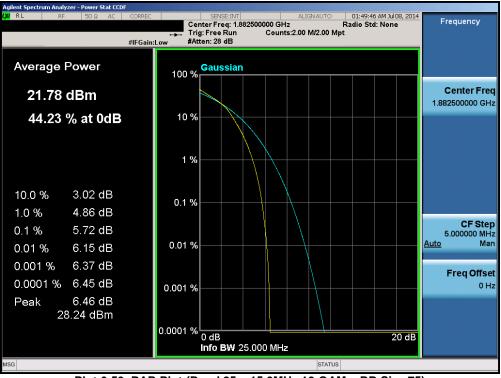
Plot 6-57. PAR Plot (Band 25 – 1.4MHz 16-QAM – RB Size 6)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	SAMSUNG	Reviewed by: Quality Manager
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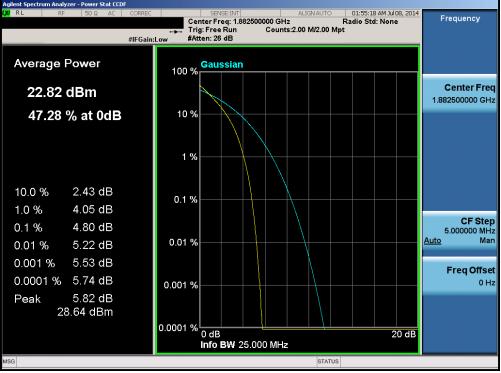


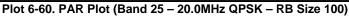


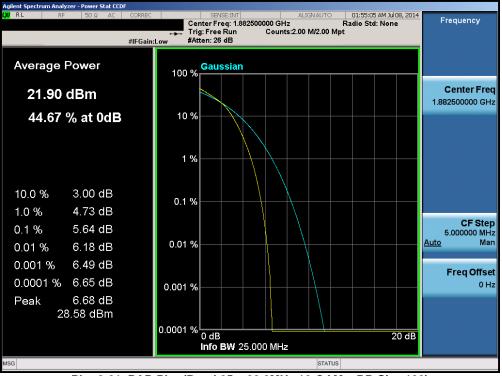
Plot 6-59. PAR Plot (Band 25 – 15.0MHz 16-QAM – RB Size 75)

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Plot 6-61. PAR Plot (Band 25 - 20.0MHz 16-QAM - RB Size 100)

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6.6 Radiated Power (EIRP) §24.232(c) §27.50(h.2)

Test Overview

Equivalent Isotropic Radiated Power (EIRP) measurements are performed using the substitution method described in ANSI/TIA-603-C-2004 with the EUT transmitting into an integral antenna. Measurements on signals operating below 1GHz are performed using vertically polarized tuned dipole antennas. Measurements on signals operating above 1GHz are performed using vertically polarized broadband horn antennas. All measurements are performed as RMS average measurements while the EUT is operating at its maximum duty cycle, at maximum power, and at the appropriate frequencies.

Test Procedures Used

KDB 971168 v02r01 - Section 5.2.1

ANSI/TIA-603-C-2004 - Section 2.2.17

Test Settings

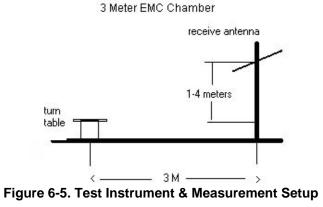
- 1. Radiated power measurements are performed using the signal analyzer's "channel power" measurement capability for signals with continuous operation. For signals with burst transmission, the signal analyzer's "time domain power" measurement capability is used
- 2. RBW = 1 5% of the expected OBW, not to exceed 1MHz
- 3. VBW \geq 3 x RBW
- 4. Span = 1.5 times the OBW
- 5. No. of sweep points \geq 2 x span / RBW
- 6. Detector = RMS
- 7. Trigger is set to "free run" for signals with continuous operation with the sweep times set to "auto". Trigger is set to enable triggering only on full power bursts with the sweep time set less than or equal to the transmission burst duration
- 8. The integration bandwidth was roughly set equal to the measured OBW of the signal for signals with continuous operation. For signals with burst transmission, the "gating" function was enabled to ensure that measurements are performed during times in which the transmitter is operating at its maximum power
- 9. Trace mode = trace averaging (RMS) over 100 sweeps
- 10. The trace was allowed to stabilize

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Test Setup

The EUT and measurement equipment were set up as shown in the diagram below.



Test Notes

- 1) The EUT was tested in three orthogonal planes and in all possible test configurations and positioning. The "H" positioning is defined with the EUT lying flat on the test surface, the "H2" positioning is defined with the EUT standing up on its side, and the "V" positioning is defined with the EUT standing up on its side, and the "V" positioning is defined with the EUT standing upright. The worst case emissions are reported with the EUT positioning, modulations, RB sizes and offsets, and channel bandwidth configurations shown in the tables below.
- 2) The EUT is supplied with a new fully-recharged battery. The battery for this model B500BU contains an embedded NFC antenna.

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Frequency [MHz]	Channel Bandwidth [MHz]	Mod.	Battery	RB Size/Offset	Substitute Level [dBm]	Ant. Gain [dBi]	Ant. Pol. [H/V]	EUT Pol.	EIRP [dBm]	EIRP [Watts]	Margin [dB]
1850.70	1.4	QPSK	Standard	1 / 0	9.53	9.60	V	V	19.13	0.082	-13.88
1882.50	1.4	QPSK	Standard	3 / 2	10.01	9.53	V	V	19.54	0.090	-13.47
1914.30	1.4	QPSK	Standard	1 / 5	9.43	9.47	V	V	18.90	0.078	-14.11
1850.70	1.4	16-QAM	Standard	1 / 0	8.45	9.60	V	V	18.05	0.064	-14.96
1882.50	1.4	16-QAM	Standard	1 / 5	9.32	9.53	V	V	18.85	0.077	-14.16
1914.30	1.4	16-QAM	Standard	1 / 5	8.27	9.47	V	V	17.74	0.059	-15.27
1857.50	15	QPSK	Standard	1 / 74	9.71	9.58	V	V	19.29	0.085	-13.72
1882.50	15	QPSK	Standard	1 / 74	9.78	9.53	V	V	19.31	0.085	-13.70
1907.50	15	QPSK	Standard	1 / 0	9.67	9.48	V	V	19.15	0.082	-13.86
1857.50	15	16-QAM	Standard	1 / 74	8.03	9.58	V	V	17.61	0.058	-15.40
1882.50	15	16-QAM	Standard	1 / 74	9.08	9.53	V	V	18.61	0.073	-14.40
1907.50	15	16-QAM	Standard	1 / 0	8.58	9.48	V	V	18.06	0.064	-14.95
1860.00	20	QPSK	Standard	1 / 0	9.00	9.58	V	V	18.58	0.072	-14.43
1882.50	20	QPSK	Standard	1 / 0	9.68	9.53	V	V	19.21	0.083	-13.80
1905.00	20	QPSK	Standard	1 / 0	10.00	9.48	V	V	19.48	0.089	-13.53
1860.00	20	16-QAM	Standard	1 / 0	7.84	9.58	V	V	17.42	0.055	-15.59
1882.50	20	16-QAM	Standard	1 / 0	9.07	9.53	V	V	18.60	0.072	-14.41
1905.00	20	16-QAM	Standard	1 / 0	7.99	9.48	V	V	17.47	0.056	-15.54

Table 6-2. EIRP Data (Band 25)

Frequency [MHz]	Channel Bandwidth [MHz]	Mod.	Battery	RB Size/Offset	Substitute Level [dBm]	Ant. Gain [dBi]	Ant. Pol. [H/V]	EUT Pol.	EIRP [dBm]	EIRP [Watts]	Margin [dB]
2499.00	5	QPSK	Standard	1 / 24	10.81	8.66	V	V	19.47	0.088	-13.54
2593.00	5	QPSK	Standard	1 / 24	10.18	8.72	V	V	18.90	0.078	-14.11
2687.50	5	QPSK	Standard	1 / 0	10.01	8.83	V	V	18.84	0.077	-14.17
2499.00	5	16-QAM	Standard	1 / 24	9.43	8.66	V	V	18.09	0.064	-14.92
2593.00	5	16-QAM	Standard	1 / 24	9.20	8.72	V	V	17.92	0.062	-15.09
2687.50	5	16-QAM	Standard	1 / 0	8.64	8.83	V	V	17.47	0.056	-15.54

Table 6-3. EIRP Data (Band 41)

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6.7 Frequency Stability / Temperature Variation §2.1055 §24.235 §27.54

Test Overview and Limit

Frequency stability testing is performed in accordance with the guidelines of ANSI/TIA-603-C-2004. The frequency stability of the transmitter is measured by:

- a.) **Temperature:** The temperature is varied from -30°C to +50°C in 10°C increments using an environmental chamber.
- b.) **Primary Supply Voltage:** The primary supply voltage is varied from 85% to 115% of the nominal value for non hand-carried battery and AC powered equipment. For hand-carried, battery-powered equipment, primary supply voltage is reduced to the battery operating end point which shall be specified by the manufacturer.

For Part 24 and Part 27, the frequency stability shall be sufficient to ensure that the fundamental emission stays within the authorized frequency block.

Test Procedure Used

ANSI/TIA-603-C-2004

Test Settings

- 1. The carrier frequency of the transmitter is measured at room temperature (20°C to provide a reference).
- 2. The equipment is turned on in a "standby" condition for fifteen minutes before applying power to the transmitter. Measurement of the carrier frequency of the transmitter is made within one minute after applying power to the transmitter.
- 3. Frequency measurements are made at 10°C intervals ranging from -30°C to +50°C. A period of at least one half-hour is provided to allow stabilization of the equipment at each temperature level.

Test Setup

The EUT was connected via an RF cable to a spectrum analyzer with the EUT placed inside an environmental chamber.

Test Notes

None

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Band 25 Frequency Stability Measurements §2.1055 §24.235

OPERATING FREQUENCY:	1,882,500,000	Hz
CHANNEL:	26365	-
REFERENCE VOLTAGE:	3.80	VDC

VOLTAGE (%)	POWER (VDC)	TEMP (°C)	FREQUENCY (Hz)	Freq. Dev. (Hz)	Deviation (%)
100 %	3.80	+ 20 (Ref)	1,882,499,979	-21	-0.0000011
100 %		- 30	1,882,499,970	-30	-0.0000016
100 %		- 20	1,882,500,027	27	0.0000014
100 %		- 10	1,882,499,974	-26	-0.0000014
100 %		0	1,882,499,982	-18	-0.0000010
100 %		+ 10	1,882,500,019	19	0.0000010
100 %		+ 20	1,882,499,976	-24	-0.0000013
100 %		+ 30	1,882,500,017	17	0.0000009
100 %		+ 40	1,882,499,982	-18	-0.0000010
100 %		+ 50	1,882,499,975	-25	-0.0000013
BATT. ENDPOINT	3.50	+ 20	1,882,500,018	18	0.0000010

 Table 6-4. Frequency Stability Data (Band 25)

Note:

Based on the results of the frequency stability test at the center channel the frequency deviation results measured are very small. As such it is determined that the channels at the band edge would remain inband when the maximum measured frequency deviation noted during the frequency stability tests is applied. Therefore the device is determined to remain operating in band over the temperature and voltage range as tested.

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Band 25 Frequency Stability Measurements §2.1055 §24.235

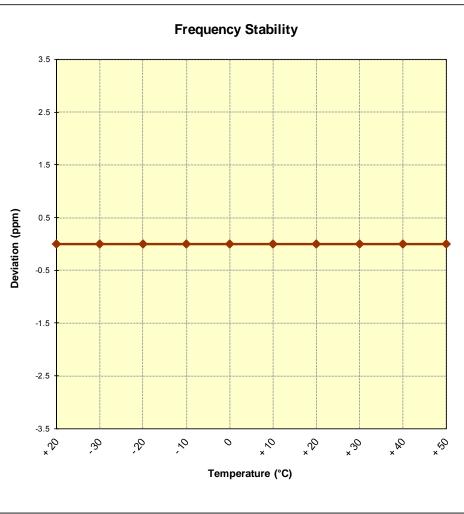


Figure 6-6. Frequency Stability Graph (Band 25)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	SAMSUNG	Reviewed by: Quality Manager
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Band 41 Frequency Stability Measurements §2.1055 §27.54

OPERATING FREQUENCY:	2,590,000,000	Hz
CHANNEL:	40590	_
REFERENCE VOLTAGE:	3.80	VDC

VOLTAGE (%)	POWER (VDC)	TEMP (°C)	FREQUENCY (Hz)	Freq. Dev. (Hz)	Deviation (%)
100 %	3.80	+ 20 (Ref)	2,589,999,970	-30	-0.0000012
100 %		- 30	2,590,000,016	16	0.0000006
100 %		- 20	2,590,000,018	18	0.0000007
100 %		- 10	2,589,999,974	-26	-0.0000010
100 %		0	2,590,000,030	30	0.0000012
100 %		+ 10	2,590,000,019	19	0.0000007
100 %		+ 20	2,589,999,971	-29	-0.0000011
100 %		+ 30	2,590,000,030	30	0.0000012
100 %		+ 40	2,589,999,973	-27	-0.0000010
100 %		+ 50	2,590,000,027	27	0.0000010
BATT. ENDPOINT	3.50	+ 20	2,590,000,016	16	0.0000006

Table 6-5. Frequency Stability Data (Band 41)

Note:

Based on the results of the frequency stability test at the center channel the frequency deviation results measured are very small. As such it is determined that the channels at the band edge would remain inband when the maximum measured frequency deviation noted during the frequency stability tests is applied. Therefore the device is determined to remain operating in band over the temperature and voltage range as tested.

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Band 41 Frequency Stability Measurements §2.1055 §27.54

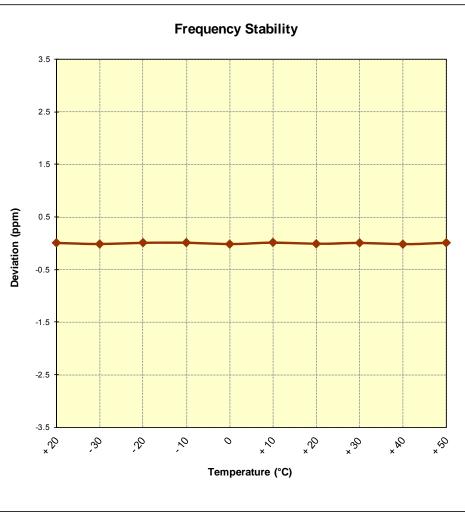


Figure 6-7. Frequency Stability Graph (Band 41)

FCC ID: A3LSPHL520		FCC Pt. 24 & 27 LTE MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	Reviewed by: Quality Manager
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7.0 CONCLUSION

The data collected relate only to the item(s) tested and show that the **Samsung Portable Handset FCC ID: A3LSPHL520** complies with all the requirements of Parts 2, 24, 27 of the FCC rules for LTE operation only.

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